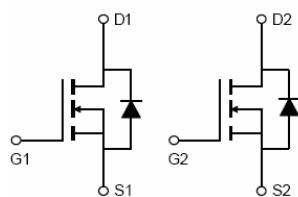


## P-Channel Enhancement Mode Field Effect Transistor



### Product Summary

- $V_{DS}$  -60V
- $I_D$  -10A
- $R_{DS(ON)}$  (at  $V_{GS} = -4.5V$ ) <135mohm
- $R_{DS(ON)}$  (at  $V_{GS} = -10V$ ) <85mohm

### General Description

- Trench Power MV MOSFET technology
- High density cell design for Low  $R_{DS(ON)}$
- High Speed switching

### Applications

- Battery protection
- Load switch
- Power management

### ■ Absolute Maximum Ratings ( $T_A=25^\circ C$ unless otherwise noted)

Parameter		Symbol	Maximum	Unit
Drain-source Voltage		$V_{DS}$	-60	V
Gate-source Voltage		$V_{GS}$	$\pm 10$	V
Drain Current <sup>B</sup>	$T_A=25^\circ C$ @ Steady State	$I_D$	-10	A
	$T_A=100^\circ C$ @ Steady State		-7	
Drain Current <sup>B</sup>	$T_A=25^\circ C$ @ Steady State	$I_D$	-10	A
	$T_A=70^\circ C$ @ Steady State		-7	
Pulsed Drain Current <sup>A</sup>		$I_{DM}$	-55	A
Single Pulse Avalanche Energy <sup>B</sup>		$E_{AS}$	31	mJ
Total Power Dissipation <sup>B</sup>	$T_A=25^\circ C$ @ Steady State	$P_D$	32	W
	$T_A=100^\circ C$ @ Steady State		12.8	
Total Power Dissipation <sup>B</sup>	$T_A=25^\circ C$ @ Steady State	$P_D$	3	W
	$T_A=70^\circ C$ @ Steady State		1.9	
Thermal Resistance Junction-to-Ambient @ Steady State <sup>B</sup>		$R_{\theta JC}$	3.9	°C / W
Thermal Resistance Junction-to-Case @ Steady State <sup>C</sup>		$R_{\theta JA}$	42	°C / W
Junction and Storage Temperature Range		$T_J, T_{STG}$	-55~+150	°C

### ■ Ordering Information (Example)

PREFERRED P/N	PACKING CODE	Marking	MINIMUM PACKAGE(pcs)	INNER BOX QUANTITY(pcs)	OUTER CARTON QUANTITY(pcs)	DELIVERY MODE
HM10DP06D	F1	HM10DP06D XXXX	5000	10000	100000	13" reel

■ Electrical Characteristics ( $T_J=25^\circ\text{C}$  unless otherwise noted)

Parameter	Symbol	Conditions	Min	Typ	Max	Units
<b>Static Parameter</b>						
Zero Gate Voltage Drain Current	$I_{DSS}$	$V_{DS}=-60\text{V}, V_{GS}=0\text{V}, T_c=25^\circ\text{C}$			-1	$\mu\text{A}$
Gate-Body Leakage Current	$I_{GSS}$	$V_{GS}= \pm 10\text{V}, V_{DS}=0\text{V}$			$\pm 100$	nA
Gate Threshold Voltage	$V_{GS(\text{th})}$	$V_{DS}= V_{GS}, I_D=-250\mu\text{A}$	-1.0		-3.0	V
Static Drain-Source On-Resistance	$R_{DS(\text{ON})}$	$V_{GS}=-4.5\text{V}, I_D=-5\text{A}$			135	$\text{m}\Omega$
		$V_{GS}=-10\text{V}, I_D=-1\text{A}$			85	
Diode Forward Voltage	$V_{SD}$	$I_S=-60\text{A}, V_{GS}=0\text{V}$		-0.8	-1.2	V
Maximum Body-Diode Continuous Current	$I_S$				-10	A
<b>Dynamic Parameters</b>						
Input Capacitance	$C_{iss}$	$V_{DS}=-10\text{V}, V_{GS}=0\text{V}, f=1\text{MHz}$		2992		$\text{pF}$
Output Capacitance	$C_{oss}$			330		
Reverse Transfer Capacitance	$C_{rss}$			272		
<b>Switching Parameters</b>						
Total Gate Charge	$Q_g$	$V_{GS}=-10\text{V}, V_{DS}=-15\text{V}, I_D=-9.1\text{A}$		72.8		$\text{nC}$
Gate Source Charge	$Q_{gs}$			6.6		
Gate Drain Charge	$Q_{gd}$			10.1		
Reverse Recovery Charge	$Q_{rr}$	$I_F=-6\text{A}, dI/dt=100\text{A/us}$		34		$\text{ns}$
Reverse Recovery Time	$t_{rr}$			67		
Turn-on Delay Time	$t_{D(\text{on})}$	$V_{GS}=-10\text{V}, V_{DS}=-15\text{V}, I_D=-6\text{A}, R_{\text{GEN}}=2.5\Omega$		7		
Turn-on Rise Time	$t_r$			33		
Turn-off Delay Time	$t_{D(\text{off})}$			130		
Turn-off Fall Time	$t_f$			132		

A. Pulse Test: Pulse Width  $\leq 300\text{us}$ , Duty cycle  $\leq 2\%$ .

B.  $R_{\theta JA}$  is the sum of the junction-to-case and case-to-ambient thermal resistance, where the case thermal reference is defined as the solder mounting surface of the drain pins.  $R_{\theta UC}$  is guaranteed by design, while  $R_{\theta JA}$  is determined by the board design. The maximum rating presented here is based on mounting on a 1 in 2 pad of 2oz copper.

## ■ Typical Performance Characteristics

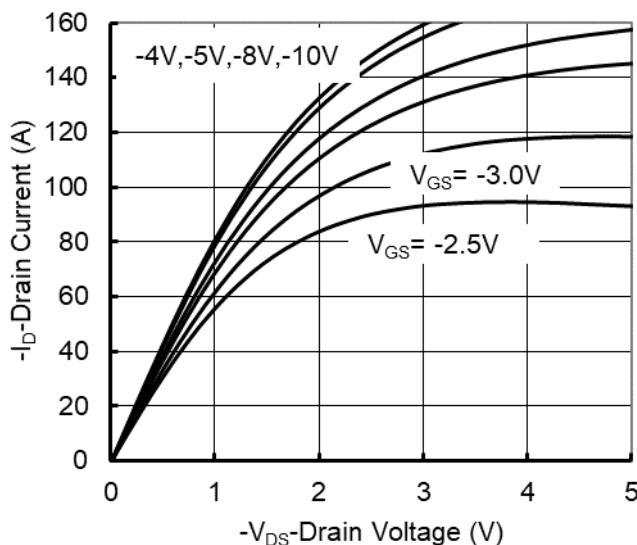


Figure 1. Output Characteristics

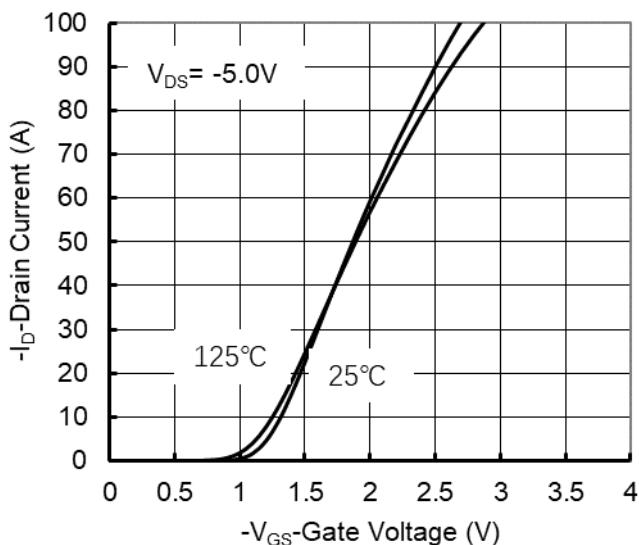


Figure 2. Transfer Characteristics

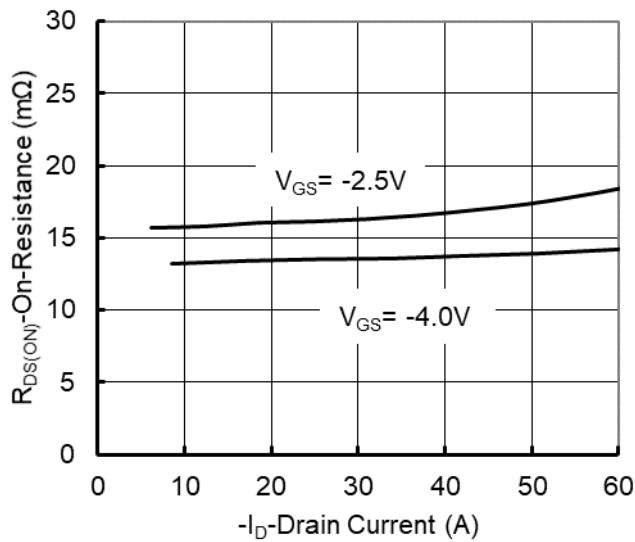


Figure 3. On-Resistance vs. Drain Current and Gate Voltage

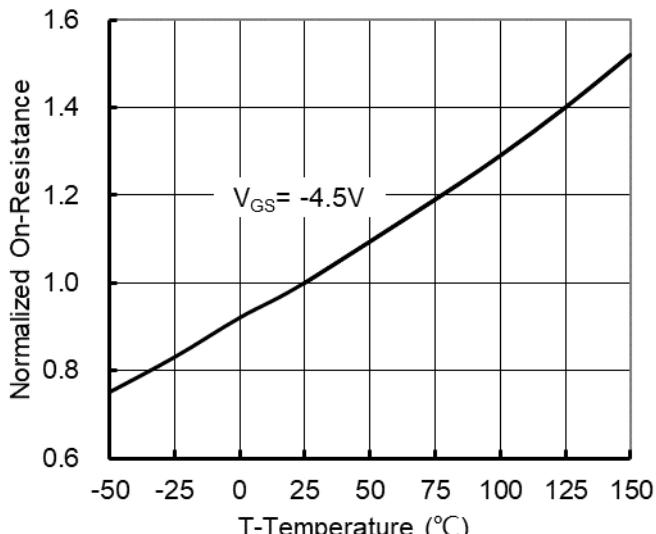


Figure 4. On-Resistance vs. Junction Temperature

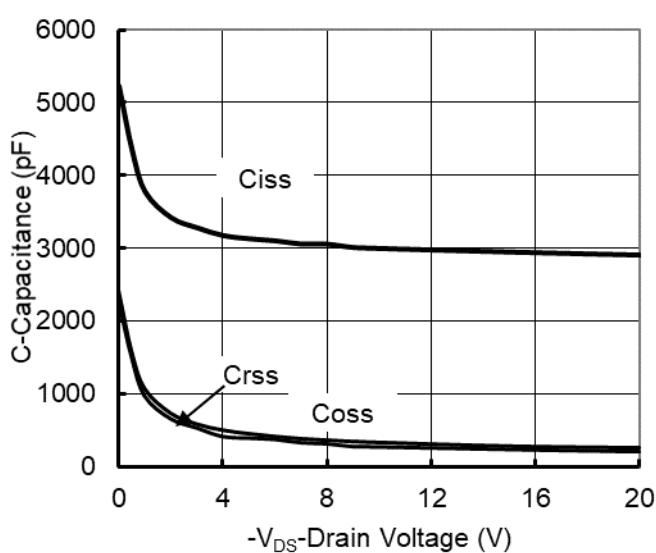


Figure 5. Capacitance Characteristics

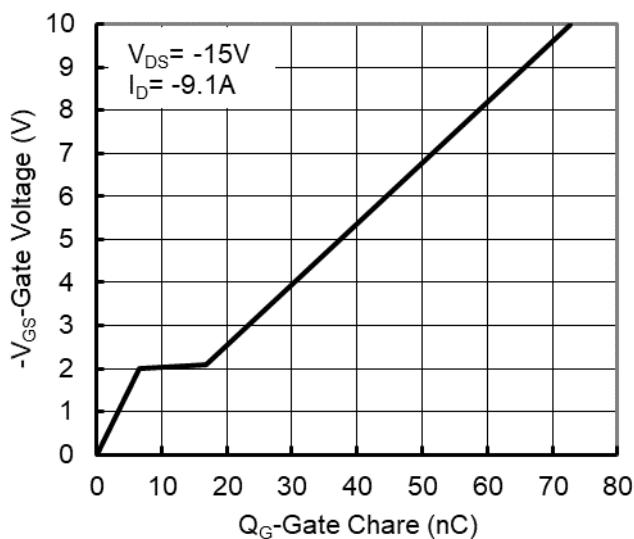
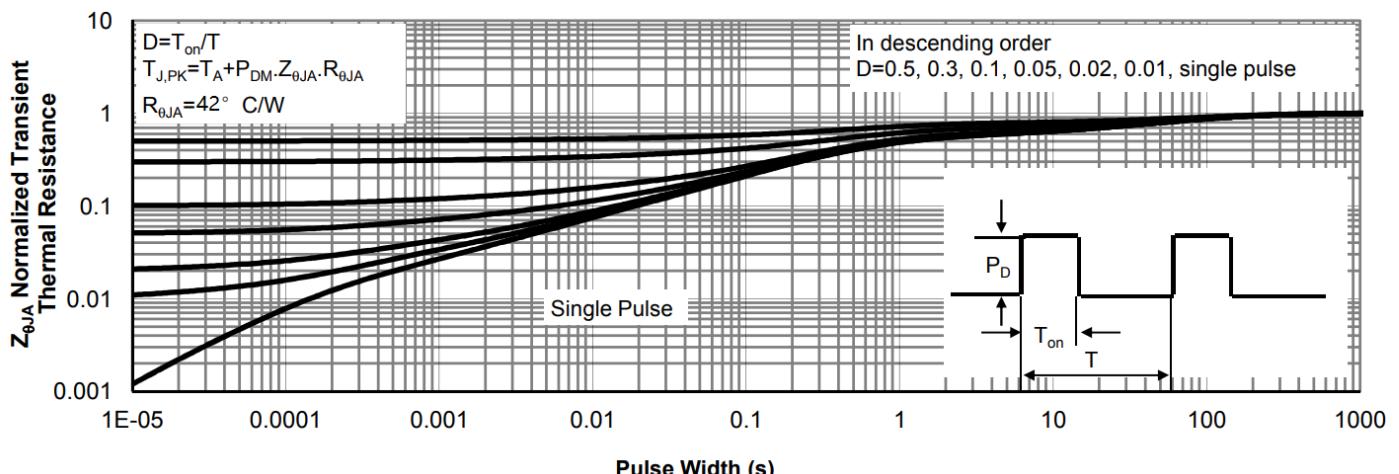
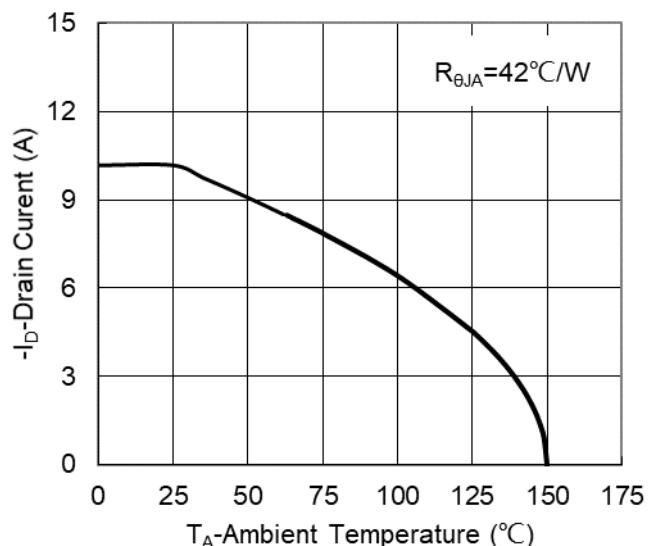
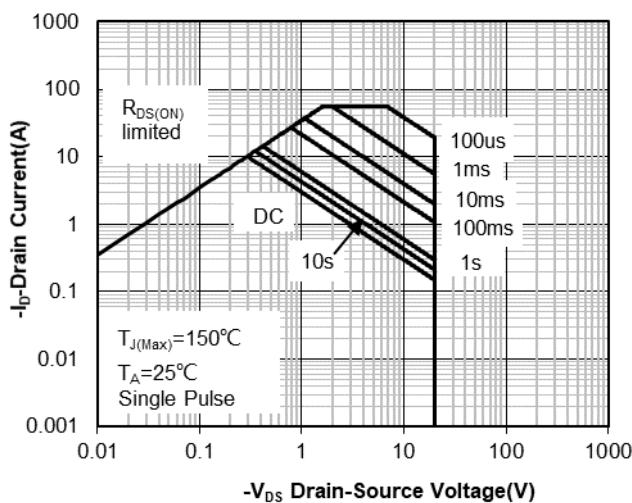
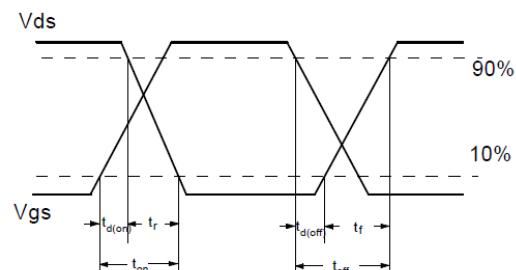
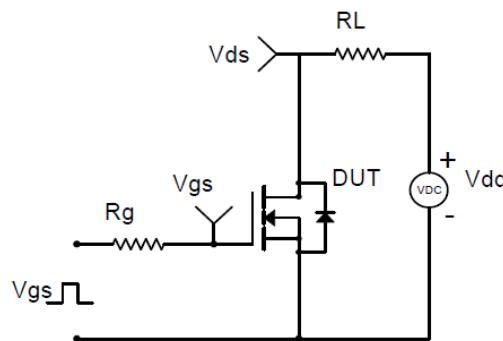
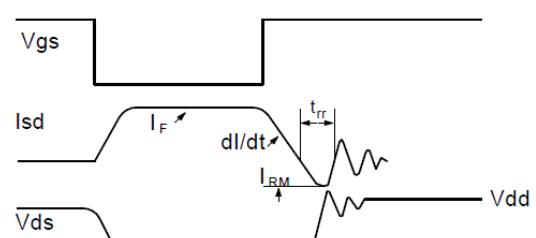
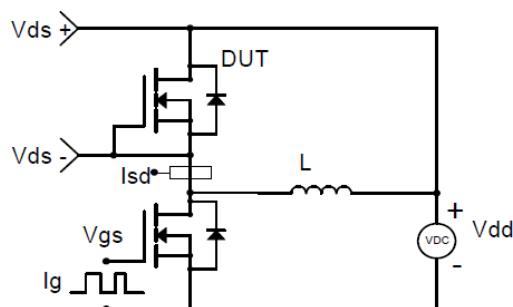


Figure 6. Gate Charge

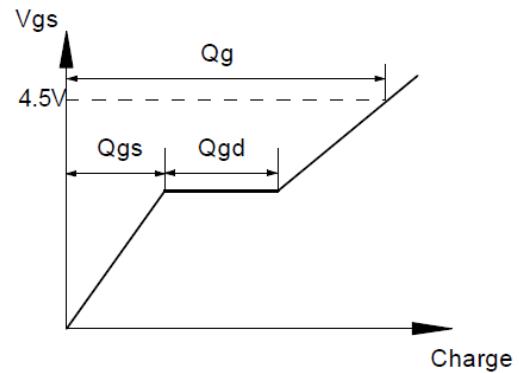
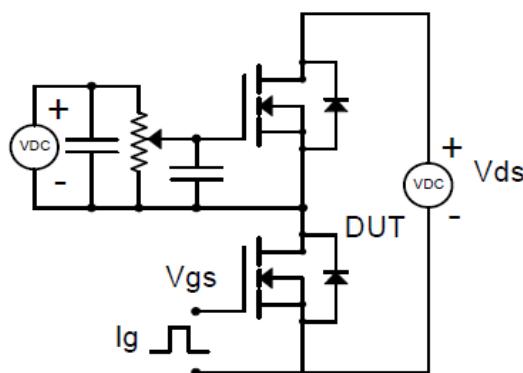




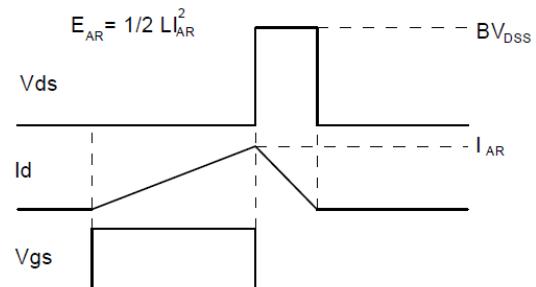
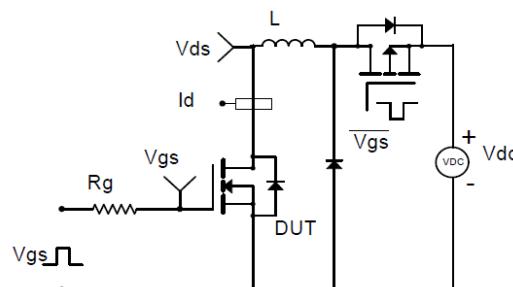
Resistive Switching Test Circuit & Waveforms



Diode Recovery Test Circuit & Waveforms

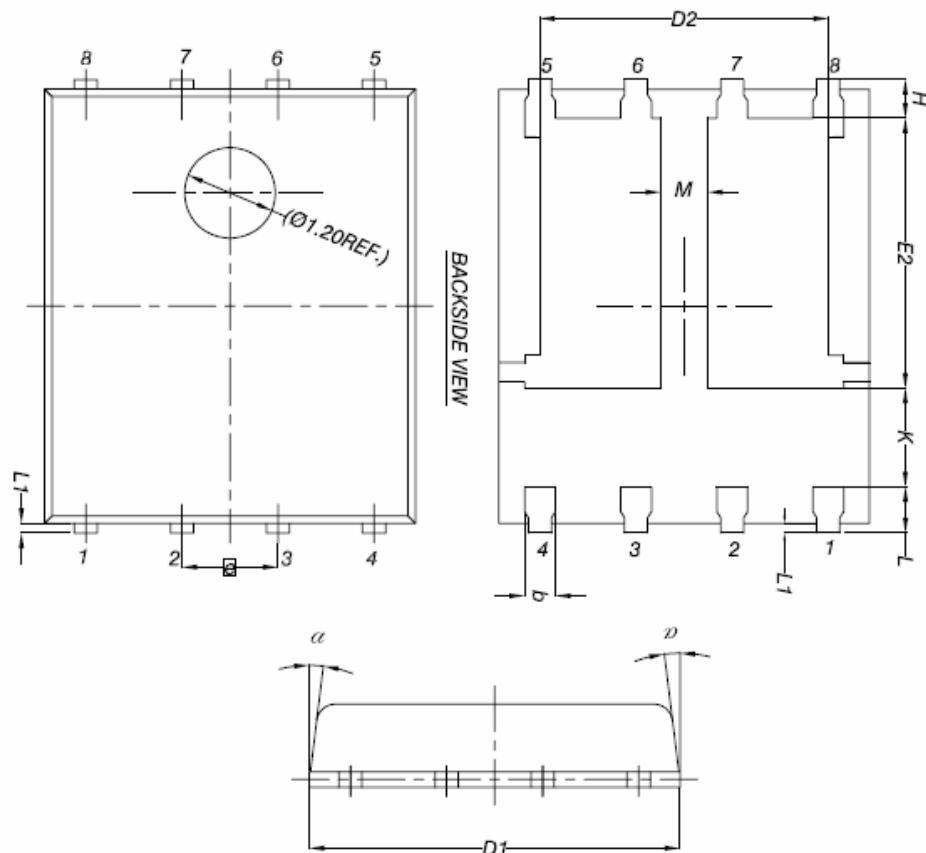


Gate Charge Test Circuit & Waveform



Unclamped Inductive Switching (UIS) Test Circuit & Waveforms

## DFN5X6-8L Package Information



DIM.	MILLIMETERS		
	MIN.	NOM.	MAX.
A	0.90	1.00	1.10
b	0.33	0.41	0.51
C	0.20	0.25	0.30
D <sub>1</sub>	4.80	4.90	5.00
D <sub>2</sub>	3.61	3.81	3.96
E	5.90	6.00	6.10
E <sub>1</sub>	5.70	5.75	5.80
E <sub>2</sub>	3.38	3.58	3.78
<b>[e] 1.27 BSC</b>			
H	0.41	0.51	0.61
K	1.10	-	-
L	0.51	0.61	0.71
L <sub>1</sub>	0.06	0.13	0.20
M	0.50	-	-
$\alpha$	0°	-	12°